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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yukio HEMMI, et al.

: ATTN: LICENSING AND  
REVIEW

SERIAL NUMBER: 09/964,624

FILED: September 28, 2001

FOR: METHOD FOR CONTROLLING WATER QUALITY IN NUCLEAR REACTOR  
AND NUCLEAR POWER PLANT TO WHICH THE METHOD IS APPLIED

STATEMENT UNDER 42 USC 2182 (AEC)

ASSISTANT COMMISSIONER FOR PATENTS  
WASHINGTON, D.C. 20231

Sir:

We, Yukio HEMMI, Kenji YAMAZAKI, Hajime HIRASAWA, being the Inventors herein, declare that we are the Applicants in the above-identified Application, and that the full facts concerning the circumstances under which the present invention was made and the relation of such invention to the performance of any work under any contract, subcontract, or arrangement entered into with or for the benefit of the Department of Energy are as follows:

1. That the above invention was made, conceived and reduced to practice entirely on the time and efforts of the Applicants and at the sole expense and for the sole benefit of Applicants' Assignee, KABUSHIKI KAISHA TOSHIBA, with offices at 1-1, Shibaura 1-Chome, Minato-Ku, Tokyo, Japan, during the course of regular employment with said company at the facilities of KABUSHIKI KAISHA TOSHIBA, at 1-1, Shibaura 1-Chome, Minato-Ku, Tokyo, Japan.

2. The invention or discovery was not made, or conceived in the course of, or in connection with, or under any contract, subcontract, or arrangement entered into with or for the benefit of the United States Atomic Energy Commission or its successors Energy Research and Development Administration or the Department of Energy.

The undersigned Inventors declare further that all statements made herein of their own knowledge are true and that all statements made on information and belief are believed to be true; and further, that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issuing thereon.

November 27, 2001  
Date

Yukio Hemmi  
Yukio HEMMI

November 27, 2001  
Date

Kenji Yamazaki  
Kenji YAMAZAKI

November 27, 2001  
Date

Hajime Hirasawa  
Hajime HIRASAWA